QUALITY

Total Quality Management

Philips Semiconductors is a Quality Company, renowned for the high quality of our products and service. We keep alive this tradition by constantly aiming towards one ultimate standard, that of zero defects. This aim is guided by our Total Quality Management (TQM) system the basis of which is outlined the following paragraphs.

QUALITY ASSURANCE

Based on ISO 9000 standards, customer standards such as FDC, QS9000 and IBM MDQ. Our factories are certified to ISO 9000 by external inspectorates.

PARTNERSHIPS WITH CUSTOMERS

PPM co-operations, design-in agreements, ship-to-stock, just-in-time, self-qualification programmes and application support.

PARTNERSHIPS WITH SUPPLIERS

Ship-to-stock, statistical process control and ISO 9000 audits.

QUALITY IMPROVEMENT PROGRAMME

Continuous process and system improvement, design improvement, complete use of statistical process control, realization of our final objective of zero defects, and logistics improvement by ship-to-stock and just-in-time agreements.

Advanced quality planning

During the design and development of new products and processes, quality is built-in by advanced quality planning. Through failure-mode-and-effect analysis the critical parameters are detected and measures taken to ensure good performance on these parameters. The capability of process steps is also planned in this phase in preparation for production under statistical process control.

Product conformance

The assurance of product conformance is an integral part of our quality assurance (QA) practice. This is achieved by:

- Incoming material management through partnerships with suppliers.
- In-line quality assurance to monitor process reproducibility during manufacture and initiate any necessary corrective action. Process steps are under statistical process control.
- Acceptance tests on finished products to verify conformance with the device specification. The test results are used for quality feedback and corrective actions. The inspection and test requirements are detailed in the general quality specifications SNW-EQ-611.
- Periodic inspections to monitor and measure the conformance of products.
- Qualification tests (see SNW-EQ-611).

Product reliability

With the increasing complexity of Original Equipment Manufacturer (OEM) equipment, component reliability must be extremely high. Our research laboratories and development departments study the failure mechanisms of semiconductors. Their studies result in design rules and process optimization for the highest built-in product reliability. Highly accelerated tests are applied to the products reliability evaluation. Rejects from reliability tests and from customer complaints are submitted to failure analysis, to result in corrective action.

Customer response

Our quality improvement depends on joint action with our customer. We need our customer's inputs and we invite constructive comments on all aspects of our performance. Please contact our local sales representative.

Recognition

The high quality of our products and services is demonstrated by many Quality Awards granted by major customers and international organizations.

PRO ELECTRON TYPE NUMBERING SYSTEM

Basic type number

This type designation code applies to non-microwave discrete semiconductor devices (not integrated circuits), multiples of such devices, semiconductor chips and Darlington transistors. Only code letters relevant to the devices in this data handbook are given here.

FIRST LETTER

The first letter gives information about the material for the active part of the device.

B Silicon or other material with a band gap of 1 to 1.3 eV

SECOND LETTER

The second letter indicates the function for which the device is primarily designed. The same letter can be used for multi-chip devices with similar elements.

G Multiple of dissimilar devices/miscellaneous devices; e.g. oscillators. Also with special third letter; see under Section “Serial number”

L Transistor; power, high frequency

SERIAL NUMBER

For devices primarily intended for industrial or professional equipment, the serial number comprises one letter (Z, Y, X, etc.) and two to four figures running from 10 to 9999.

Version letter

A letter may be added to the basic type number to indicate minor electrical or mechanical variants of the basic type.

RATING SYSTEMS

The rating systems described are those recommended by the International Electrotechnical Commission (IEC) in its publication number 134.

Definitions of terms used

ELECTRONIC DEVICE

An electronic tube or valve, transistor or other semiconductor device. This definition excludes inductors, capacitors, resistors and similar components.

CHARACTERISTIC

A characteristic is an inherent and measurable property of a device. Such a property may be electrical, mechanical, thermal, hydraulic, electro-magnetic or nuclear, and can be expressed as a value for stated or recognized conditions. A characteristic may also be a set of related values, usually shown in graphical form.

BOGEY ELECTRONIC DEVICE

An electronic device whose characteristics have the published nominal values for the type. A bogey electronic device for any particular application can be obtained by considering only those characteristics that are directly related to the application.

RATING

A value that establishes either a limiting capability or a limiting condition for an electronic device. It is determined for specified values of environment and operation, and may be stated in any suitable terms. Limiting conditions may be either maxima or minima.

RATING SYSTEM

The set of principles upon which ratings are established and which determine their interpretation. The rating system indicates the division of responsibility between the device manufacturer and the circuit designer, with the object of ensuring that the working conditions do not exceed the ratings.

Absolute maximum rating system

Absolute maximum ratings are limiting values of operating and environmental conditions applicable to any electronic device of a specified type, as defined by its published data, which should not be exceeded under the worst probable conditions.

These values are chosen by the device manufacturer to provide acceptable serviceability of the device, taking no responsibility for equipment variations, environmental variations, and the effects of changes in operating conditions due to variations in the characteristics of the device under consideration and of all other electronic devices in the equipment.

The equipment manufacturer should design so that, initially and throughout the life of the device, no absolute maximum value for the intended service is exceeded with any device, under the worst probable operating conditions with respect to supply voltage variation, equipment component variation, equipment control adjustment, load variations, signal variation, environmental conditions, and variations in characteristics of the device under consideration and of all other electronic devices in the equipment.

Design maximum rating system

Design maximum ratings are limiting values of operating and environmental conditions applicable to a bogey electronic device of a specified type as defined by its published data, and should not be exceeded under the worst probable conditions.

These values are chosen by the device manufacturer to provide acceptable serviceability of the device, taking responsibility for the effects of changes in operating conditions due to variations in the characteristics of the electronic device under consideration.

The equipment manufacturer should design so that, initially and throughout the life of the device, no design maximum value for the intended service is exceeded with a bogey electronic device, under the worst probable operating conditions with respect to supply voltage variation, equipment component variation, variation in characteristics of all other devices in the equipment, equipment control adjustment, load variation, signal variation and environmental conditions.

Design centre rating system

Design centre ratings are limiting values of operating and environmental conditions applicable to a bogey electronic device of a specified type as defined by its published data, and should not be exceeded under normal conditions.

These values are chosen by the device manufacturer to provide acceptable serviceability of the device in average applications, taking responsibility for normal changes in operating conditions due to rated supply voltage variation, equipment component variation, equipment control adjustment, load variation, signal variation, environmental conditions, and variations in the characteristics of all electronic devices.

The equipment manufacturer should design so that, initially, no design centre value for the intended service is exceeded with a bogey electronic device in equipment operating at the stated normal supply voltage.

LETTER SYMBOLS

The letter symbols for transistors and signal diodes detailed in this section are based on IEC publication number 148.

Letter symbols for currents, voltages and powers

BASIC LETTERS

I, i	current
V, v	voltage
P, p	power.

Upper-case letter symbols are used to represent all values except instantaneous values that vary with time, these are represented by lower-case letters.

SUBSCRIPTS

A, a	anode terminal
(AV), (av)	average value
B, b	base terminal
C, c	collector terminal
D, d	drain terminal
E, e	emitter terminal
F, f	forward
G, g	gate terminal
K, k	cathode terminal
M, m	peak value
O, o	as third subscript: the terminal not mentioned is open-circuit
R, r	as first subscript: reverse. As second subscript: repetitive. As third subscript: with a specified resistance between the terminal not mentioned and the reference terminal
(RMS), (rms)	root-mean-square value
S, s	as first or second subscript: source terminal (FETs only). As second subscript: non-repetitive (not FETs). As third subscript: short circuit between the terminal not mentioned and the reference terminal
X, x	specified circuit
Z, z	replaces R to indicate the actual working voltage, current or power of voltage reference and voltage reference diodes.

No additional subscript is used for DC values.

Upper-case subscripts are used for the indication of:

- Continuous (DC) values (without signal), e.g. I_B
- Instantaneous total values, e.g. i_B
- Average total values, e.g. $I_{B(AV)}$
- Peak total values, e.g. I_{BM}
- Root-mean-square total values, e.g. $I_{B(RMS)}$.

Lower-case subscripts are used for the indication of values applying to the varying component alone:

- Instantaneous values, e.g. i_b
- Root-mean-square values, e.g. $I_{b(rms)}$
- Peak values, e.g. I_{bm}
- Average values, e.g. $I_{b(av)}$.

If more than one subscript is used, the subscript for which both styles exist are either all upper-case or all lower-case.

ADDITIONAL RULES FOR SUBSCRIPTS

Transistor currents

If it is necessary to indicate the terminal carrying the current, this should be done by the first subscript (conventional current flow from the external circuit into the terminal is positive).

Examples: I_B, i_B, i_b, I_{bm}.

Diode currents

To indicate a forward current (conventional current flow into the anode terminal), the subscript F or f should be used. For a reverse current (conventional current flow out of the anode terminal), the subscript R or r should be used.

Examples: I_F, I_R, i_F, $I_{f(rms)}$.

Transistor voltages

If it is necessary to indicate the points between which a voltage is measured, this should be done by the first two subscripts. The first subscript indicates the terminal at which the voltage is measured and the second the reference terminal or the circuit node. Where there is no possibility of confusion, the second subscript may be omitted.

Examples: V_{BE}, v_{BE}, v_{be}, V_{bem}.

Diode voltages

To indicate a forward voltage (anode positive with respect to cathode), the subscript F or f should be used. For a reverse voltage (anode negative with respect to cathode), the subscript R or r should be used.

Examples: V_F, V_R, v_F, V_{rm}.

Supply voltages or currents

Supply voltages or supply currents are indicated by repeating the appropriate terminal subscript.

Examples: V_{CC}, I_{EE}.

If it is necessary to indicate a reference terminal, this should be done by a third subscript.

Example: V_{CCE}.

Subscripts for devices with more than one terminal of the same kind

If a device has more than one terminal of the same kind, the subscript is formed by the appropriate letter for the terminal, followed by a number. In the case of multiple subscripts, hyphens may be necessary to avoid confusion.

Examples:

I_{B2} continuous (DC) current flowing into the second base terminal

$V_{B2\text{-}E}$ continuous (DC) voltage between the terminals of second base and emitter terminals.

Subscripts for multiple devices

For multiple unit devices, the subscripts are modified by a number preceding the letter subscript. In the case of multiple subscripts, hyphens may be necessary to avoid confusion.

Examples:

I_{2C} continuous (DC) current flowing into the collector terminal of the second unit

$V_{1C\text{-}2C}$ continuous (DC) voltage between the collector terminals of the first and second units.

Application of the rules

Figure 1 represents a transistor collector current as a function of time. It comprises a continuous (DC) current and a varying component.

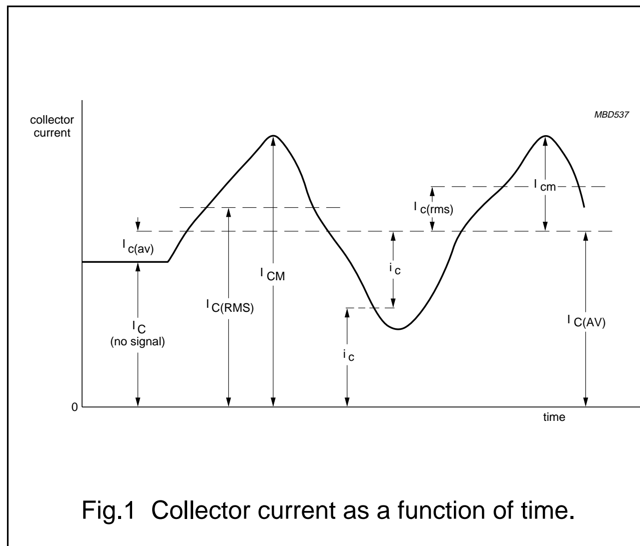


Fig.1 Collector current as a function of time.

Letter symbols for electrical parameters

DEFINITION

For the purpose of this publication, the term 'electrical parameter' applies to four-pole matrix parameters, elements of electrical equivalent circuits, electrical impedances and admittances, inductances and capacitances.

BASIC LETTERS

The following list comprises the most important basic letters used for electrical parameters of semiconductor devices.

B, b	susceptance (imaginary part of an admittance)
C	capacitance
G, g	conductance (real part of an admittance)
H, h	hybrid parameter
L	inductance
R, r	resistance (real part of an impedance)
X, x	reactance (imaginary part of an impedance)
Y, y	admittance
Z, z	impedance.

Upper-case letters are used for the representation of:

- Electrical parameters of external circuits and of circuits in which the device forms only a part.
- All inductances and capacitances.

Lower-case letters are used for the representation of electrical parameters inherent in the device, with the exception of inductances and capacitances.

SUBSCRIPTS

General subscripts

The following list comprises the most important general subscripts used for electrical parameters of semiconductor devices.

F, f	forward (forward transfer)
I, i (or 1)	input
L, l	load
O, o (or 2)	output
R, r	reverse (reverse transfer)
S, s	source.

Examples: Z_s, h_f, h_F.

The upper-case variant of a subscript is used for the designation of static (DC) values.

Examples:

h_{FE}	static value of forward current transfer ratio in common-emitter configuration (DC current gain)
R_E	DC value of the external emitter resistance.

The static value is the slope of the line from the origin to the operating point on the appropriate characteristic curve, i.e. the quotient of the appropriate electrical quantities at the operating point.

The lower-case variant of a subscript is used for the designation of small-signal values.

Examples:

h_{fe}	small-signal value of the short-circuit forward current transfer ratio in common-emitter configuration
$Z_e = R_e + jX_e$	small-signal value of the external impedance.

If more than one subscript is used, subscripts for which both styles exist are either all upper-case or all lower-case.

Examples: h_{FE}, y_{RE}, h_{fe}.

Subscripts for four-pole matrix parameters

The first letter subscript (or double numeric subscript) indicates input, output, forward transfer or reverse transfer.

Examples: h_i (or h_{11}), h_o (or h_{22}), h_f (or h_{21}), h_r (or h_{12}).

A further subscript is used for the identification of the circuit configuration. When no confusion is possible, this further subscript may be omitted.

Examples: h_{fe} (or h_{21e}), h_{FE} (or h_{21E}).

DISTINCTION BETWEEN REAL AND IMAGINARY PARTS

If it is necessary to distinguish between real and imaginary parts of electrical parameters, no additional subscripts should be used. If basic symbols for the real and imaginary parts exist, these may be used.

Examples: $Z_i = R_i + jX_i$, $y_{fe} = g_{fe} + jb_{fe}$.

If such symbols do not exist, or if they are not suitable, the following notation is used:

Examples:

Re (h_{ib}) etc. for the real part of h_{ib}

Im (h_{ib}) etc. for the imaginary part of h_{ib}.

Scattering parameters

In distinction to the conventional h-, y- and z-parameters, scattering parameters (s-parameters) relate to travelling wave conditions. Fig.2 shows a two-port network with the incident and reflected waves a_1, b_1, a_2 and b_2.

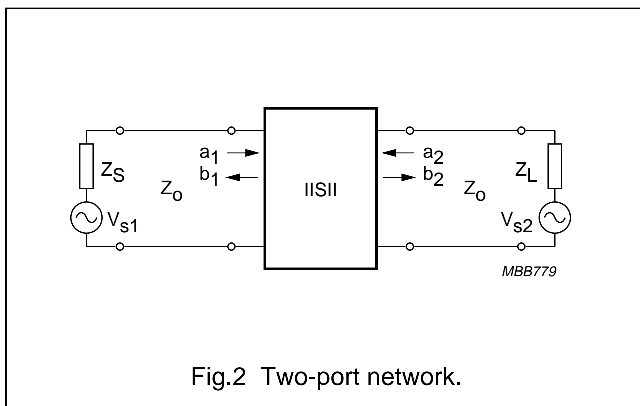


Fig.2 Two-port network.

From Fig.2: $a_1 = \frac{V_{i1}}{\sqrt{Z_0}}$; $a_2 = \frac{V_{i2}}{\sqrt{Z_0}}$; $b_1 = \frac{V_{r1}}{\sqrt{Z_0}}$; $b_2 = \frac{V_{r2}}{\sqrt{Z_0}}$

The squares of these quantities have the dimension of power.

Z_0 = characteristic impedance of the transmission line in which the two-port is connected

V_i = incident voltage

V_r = reflected (generated) voltage.

The four-pole equations for s-parameters are:

$b_1 = s_{11}a_1 + s_{12}a_2$

$b_2 = s_{21}a_1 + s_{22}a_2$.

Using the subscripts i for 11, r for 12, f for 21 and o for 22, it follows that:

$$s_i = s_{11} = \frac{b_1}{a_1} \mid a_2 = 0$$

$$s_r = s_{12} = \frac{b_1}{a_2} \mid a_1 = 0$$

$$s_f = s_{21} = \frac{b_2}{a_1} \mid a_2 = 0$$

$$s_o = s_{22} = \frac{b_2}{a_2} \mid a_1 = 0$$

The s-parameters can be named and expressed as follows:

$s_i = s_{11}$ input reflection coefficient: the complex ratio of the reflected wave and the incident wave at the input, under the conditions $Z_L = Z_0 = 50\ \Omega$ and $V_{s2} = 0$

$s_r = s_{12}$ reverse transmission coefficient: the complex ratio of the generated wave at the input and the incident wave at the output, under the conditions $Z_S = Z_0 = 50\ \Omega$ and $V_{s1} = 0$

$s_f = s_{21}$ forward transmission coefficient: the complex ratio of the generated wave at the output and the incident wave at the input, under the conditions $Z_L = Z_0 = 50\ \Omega$ and $V_{s2} = 0$

$s_o = s_{22}$ output reflection coefficient: the complex ratio of the reflected wave and the incident wave at the output, under the conditions $Z_S = Z_0 = 50\ \Omega$ and $V_{s1} = 0$.

SOLDERING SMD TRANSISTORS

Introduction

There are two basic forms of electronic component construction, those with leads for through-hole mounting and microminiature types for surface mounting (SMD). Through-hole mounting gives a very rugged construction and uses well established soldering methods. Surface mounting has the advantages of high packing density plus high-speed automated assembly. Surface mounting techniques are complex and this chapter gives only a simplified overview of the subject. For a more detailed description of soldering techniques, refer to Data Handbook SC18 "Discrete Semiconductor Packages", ordering number 9397 750 02418.

Although many electronic components are available as surface mounting types, some are not and this often leads to the use of through-hole as well as surface mounting components on one substrate (a mixed print). The mix of components affects the soldering methods that can be applied. A substrate having SMDs mounted on one or both sides but no through-hole components is likely to be suitable for reflow or wave soldering. A double sided mixed print that has through-hole components and some SMDs on one side and densely packed SMDs on the other normally undergoes a sequential combination of reflow and wave soldering. When the mixed print has only through-hole components on one side and all SMDs on the other, wave soldering is usually applied.

Reflow soldering process

There are three basic process steps for single-sided PCB reflow soldering, these are:

1. Applying solder paste to the PCB
2. Component placement
3. Reflow soldering.

APPLYING SOLDER PASTE TO THE PCB

Solder paste can be applied to the PCBs solder lands by one of either three methods: dispensing, screen or stencil printing.

Dispensing is flexible but is slow, and only suitable for pitches of 0.65 mm and above.

With screen printing, a fine-mesh screen is placed over the PCB and the solder paste is forced through the mesh onto the solder lands of the PCB. However, because of mesh aperture limitations (emulsion resolution), this method is only suitable for solder paste deposits of 300 μm and wider.

Stencil printing is similar to screen printing, except that a metal stencil is used instead of a fine-mesh screen. The stencil is usually made of stainless steel or bronze and should be 150 to 200 μm thick. A squeegee is passed across the stencil to force solder paste through the apertures in the stencil and onto the solder lands on the PCB. It does not suffer from the same limitations as the other two printing methods and so is the preferred method currently available.

COMPONENT PLACEMENT

The position of the component with respect to the solder lands is an important factor in the final result of the assembly process. A misaligned component can lead to unreliable joints, open circuits and/or bridges between leads.

The placement accuracy is defined as the maximum permissible deviation of the component outline or component leads, with respect to the actual position of the solder land pattern belonging to that component or component leads on the circuit board.

REFLOW SOLDERING

There are several methods available to provide the heat to reflow the solder paste, such as convection, hot belt, hot gas, vapour phase and resistance soldering. The preferred method is, however, convection reflow.

Convection reflow

With this method, the PCBs passes through an oven where it is preheated, reflow soldered and cooled (see Fig.3). If the heating rate of the board and components are similar, however, preheating is not necessary.

During the reflow soldering process, all parts of the board must be subjected to an accurate temperature/ time profile. Figure 3 shows a suitable profile framework for single-sided reflow soldering and the first side of double-sided print boards. It's important to note that this profile is for discrete semiconductor packages. The actual framework for the entire PCB could be smaller than the one shown, as other components on the board may have different process requirements.

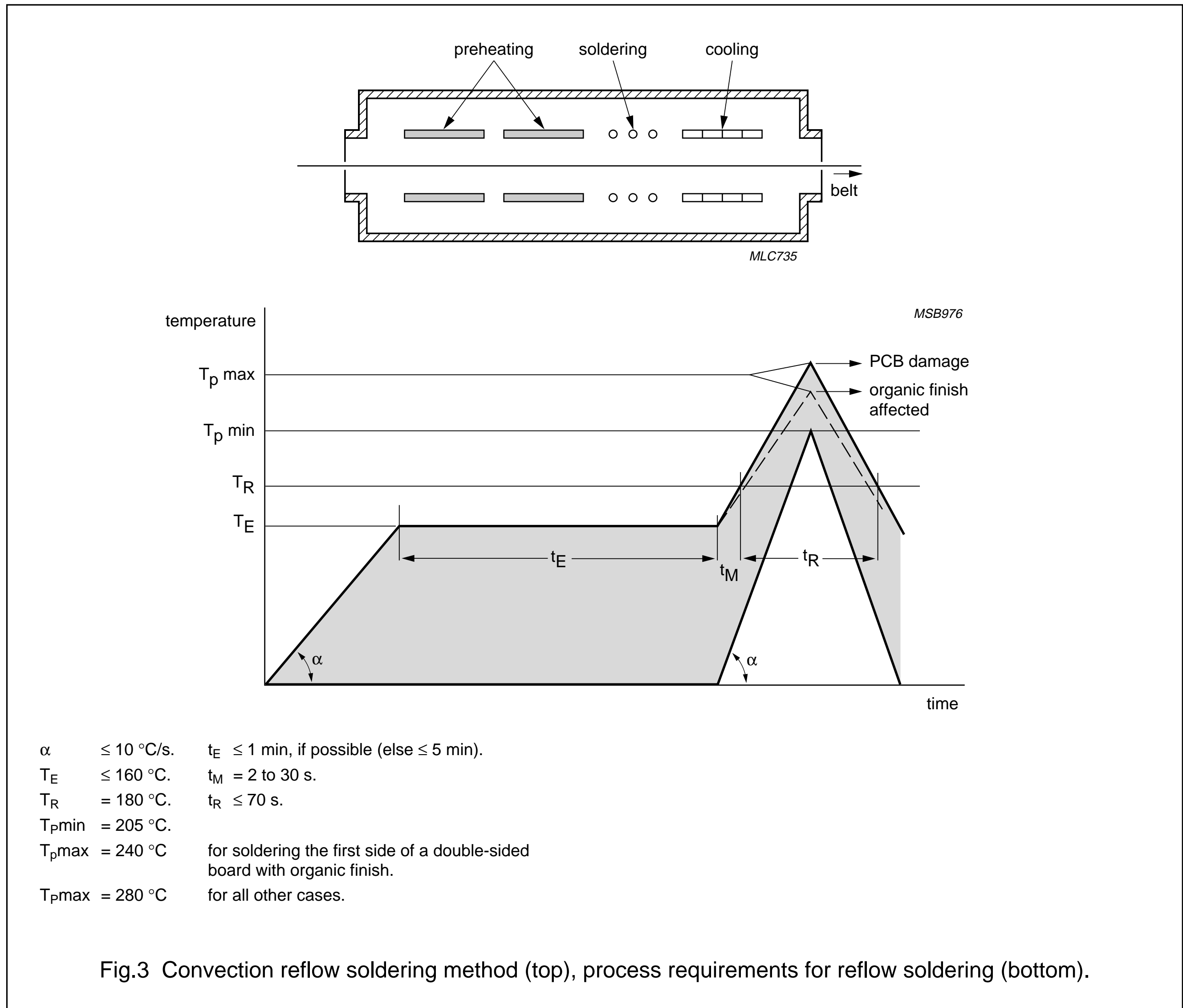


Fig.3 Convection reflow soldering method (top), process requirements for reflow soldering (bottom).

Double-wave soldering process

There are four basic process steps for double-wave soldering, these are:

1. Applying adhesive
2. Component placement
3. Curing adhesive
4. Wave soldering process.

APPLYING ADHESIVE

To hold SMDs on the board during wave soldering, it is necessary to bond the component to the PCB with one or more adhesive dots. This is done either by dispensing, stencilling or pin transfer. Dispensing is currently the most popular technique. It is flexible and allows a controlled amount of adhesive to be applied at each position. Stencil printing and pin transfer are less flexible and are mainly used for mass production.

COMPONENT PLACEMENT

Positioning components on the PCB is similar in practice to that of reflow soldering.To prevent component shift and smearing of the adhesive, board support is important while placing components.

CURING THE ADHESIVE

To provide sufficient bonding strength between component and board, the adhesive must be properly cured. The adhesive can be cured either by infrared or hot-air convection.

WAVE SOLDERING PROCESS

After applying adhesive, placing the component on the PCB and curing, the PCB can be wave soldered. The wave soldering process is basically built up from three sub-processes. These are:

1. Fluxing
2. Preheating
3. (Double) wave soldering.

Although listed here as sub-process they are in practice combined in one machine. All are served by one transport mechanism, which guides the PCBs at an incline through the soldering machine. It's important to note that the PCB must be loaded into the machine so that the SMDs on the board come into direct contact with the solder wave (see Fig.4).

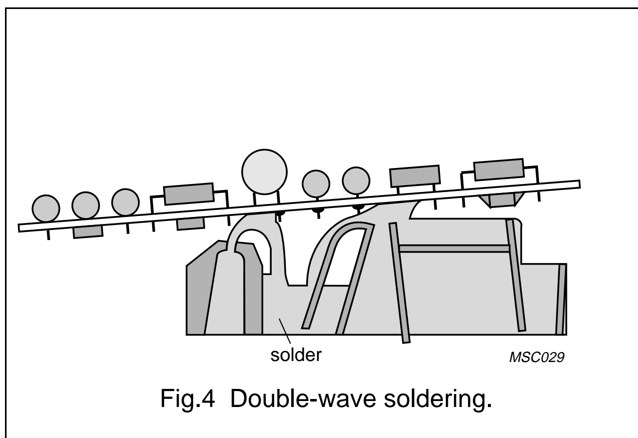


Fig.4 Double-wave soldering.

Fluxing

Fluxing is necessary to promote wetting both of the PCB and the mounted components. This ensures a good and even solder joint. During the fluxing process, the solder side of the PCB (including the components) are covered with a thin layer of solder flux, which can be applied to the PCB either by spraying or as a foam.

Preheating

After the flux is applied, the PCB needs to be preheated. This serves several purposes: it evaporates the flux solvents, it accelerates the activity of the flux and it heats the PCB and components to reduce thermal shock.

The required pre-heat temperature depends on the type of flux used. For example, the more common low-residue fluxes require a pre-heat temperature of 120 °C (measured on the wave solder side of the PCB).

(Double) wave soldering

The PCB first passes over a highly intensive (jet) solder wave with a carefully controlled constant height. This ensures good contact with the PCB, the edges of SMDs and the leads of components near to high non-wetted bodies. The greater the board's immersion depth into this first wave, the fewer joints will be missed.

The second, smoother laminar solder wave completes formation of the solder fillet, giving an optimal soldered connection between component and PCB. It also reduces the possibility of solder bridging by taking up excessive solder.

To reduce lead/tin oxides and possibly other solder imperfection forming during soldering, the complete wave configuration can be encapsulated by an inert atmosphere such as nitrogen.

Hand soldering microminiature components

It is possible to solder microminiature components with a light-weight hand-held soldering iron, but this method has obvious drawbacks and should be restricted to laboratory use and/or incidental repairs on production circuits:

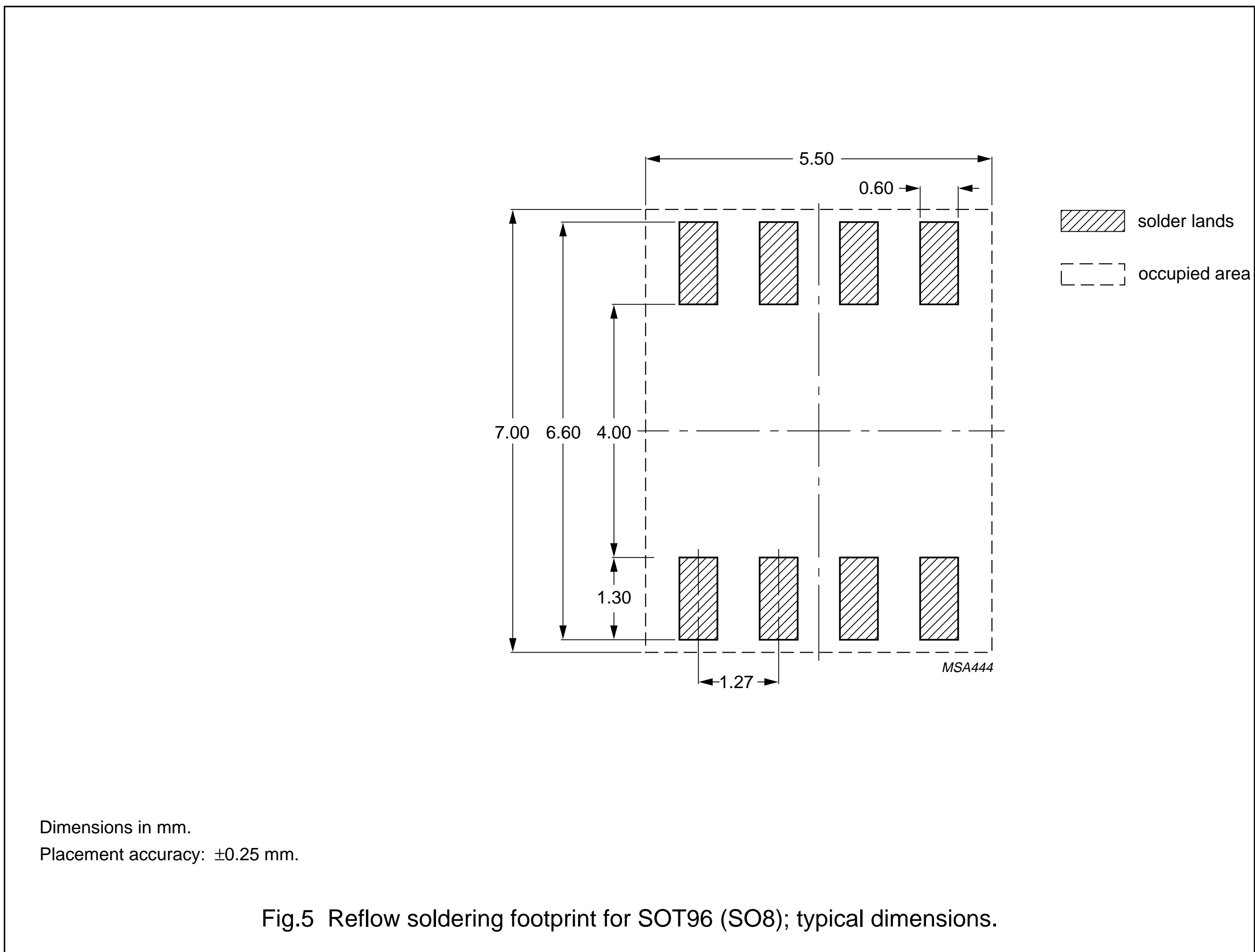
- Hand-soldering is time-consuming and therefore expensive
- The component cannot be positioned accurately and the connecting tags may come into contact with the substrate and damage it
- There is a risk of breaking the substrate and internal connections in the component could be damaged
- The component package could be damaged by the iron.

Specific recommendations for SOT409

Both the metallized ground plate and leads contribute to the heatflow. For the best results it is recommended to mount the transistor on a grounded metallized area on the printed-circuit board equipped with a large number of metallized through-holes filled with solder. A thermal resistance ($R_{th\ mb\text{-}h}$) of 0.9 K/W can be achieved if a heatsink compound is used when the printed-circuit board is mounted on the heatsink.

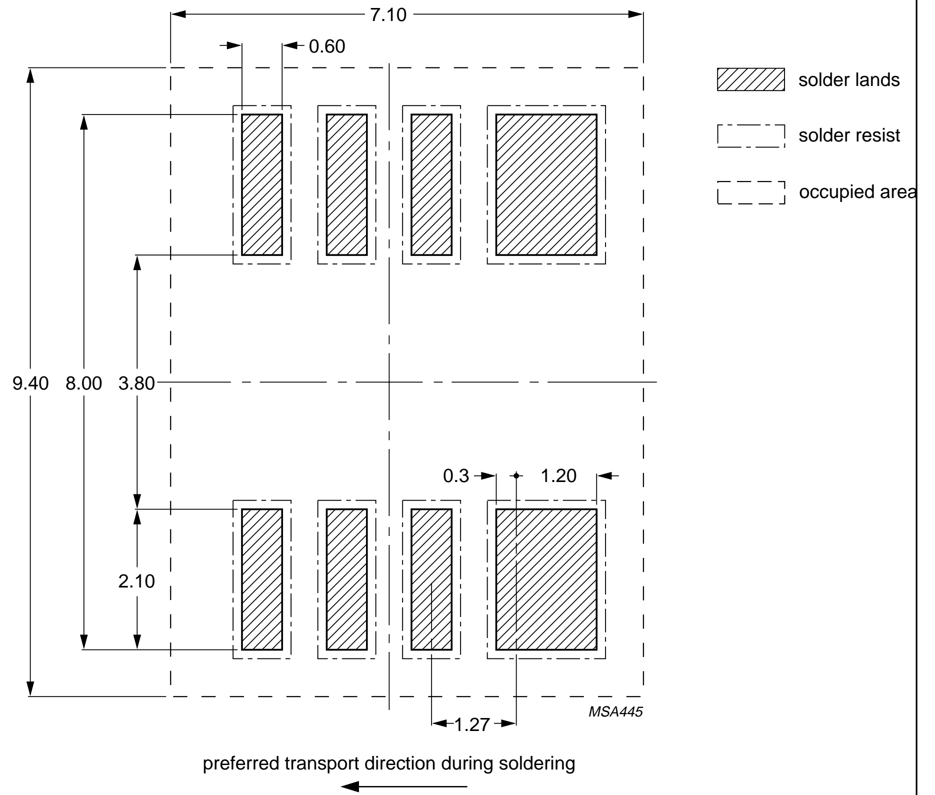
Recommended footprints

The recommended footprints for the discrete semiconductor packages contained in this book are given in Figs 5 to 9 and Fig.11.



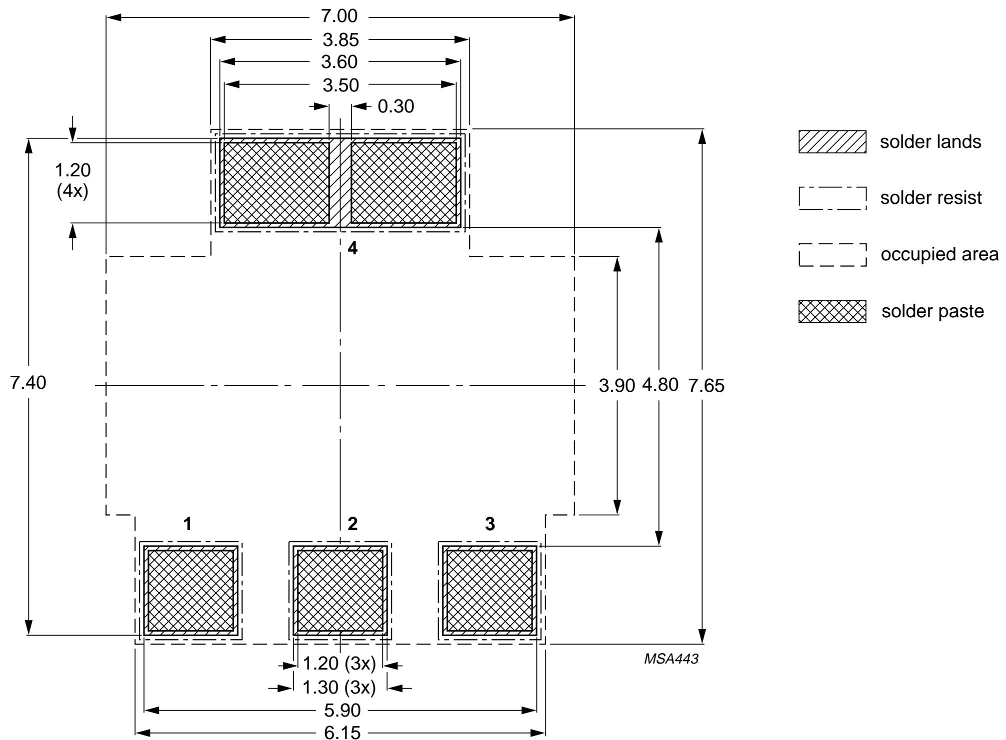
Dimensions in mm.
Placement accuracy: ±0.25 mm.

Fig.5 Reflow soldering footprint for SOT96 (SO8); typical dimensions.



Dimensions in mm.
Placement accuracy: ±0.25 mm.

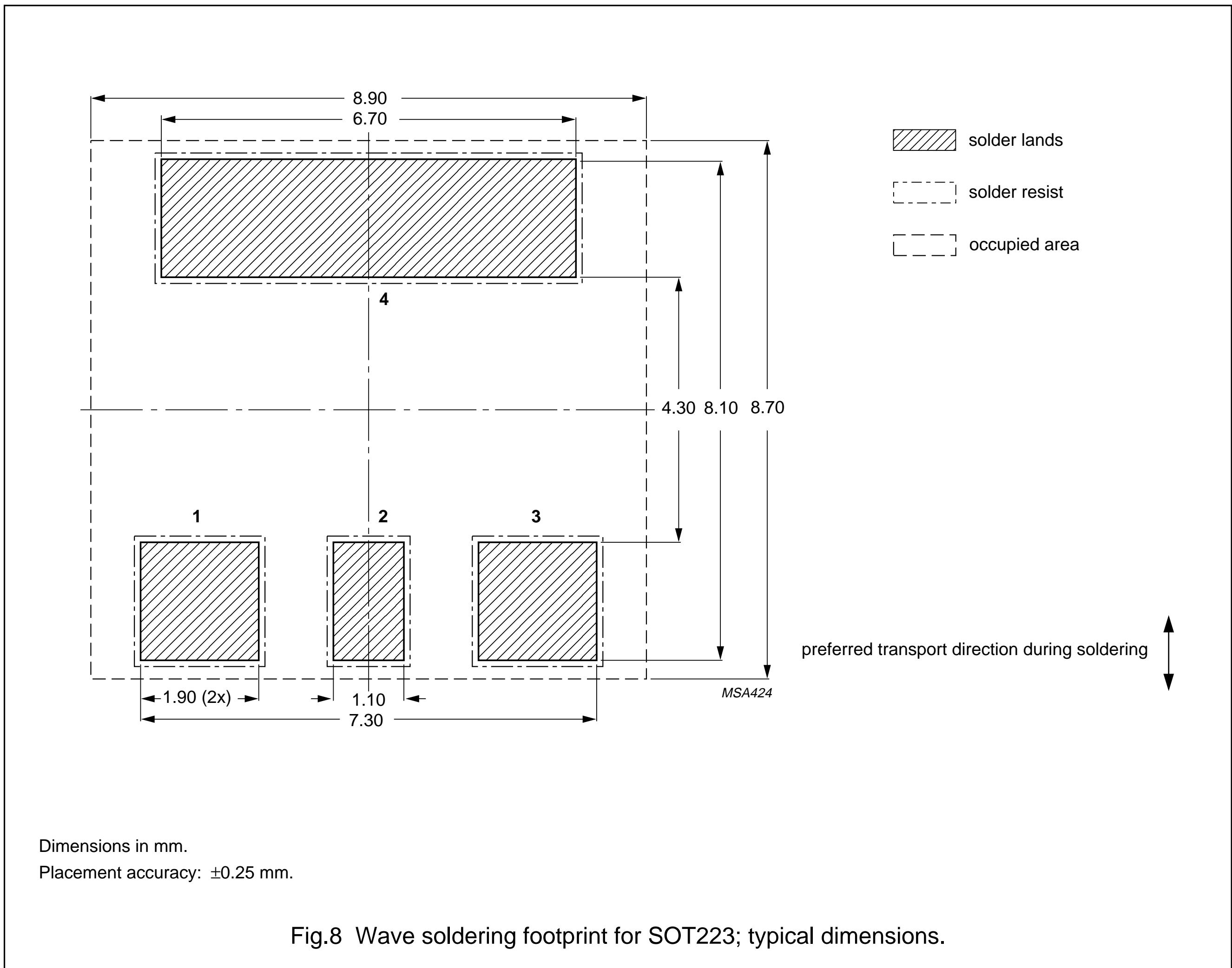
Fig.6 Wave soldering footprint for SOT96 (SO8); typical dimensions.



Dimensions in mm.

Placement accuracy: ±0.25 mm.

Fig.7 Reflow soldering footprint for SOT223; typical dimensions.



Dimensions in mm.

Placement accuracy: ±0.25 mm.

Fig.8 Wave soldering footprint for SOT223; typical dimensions.

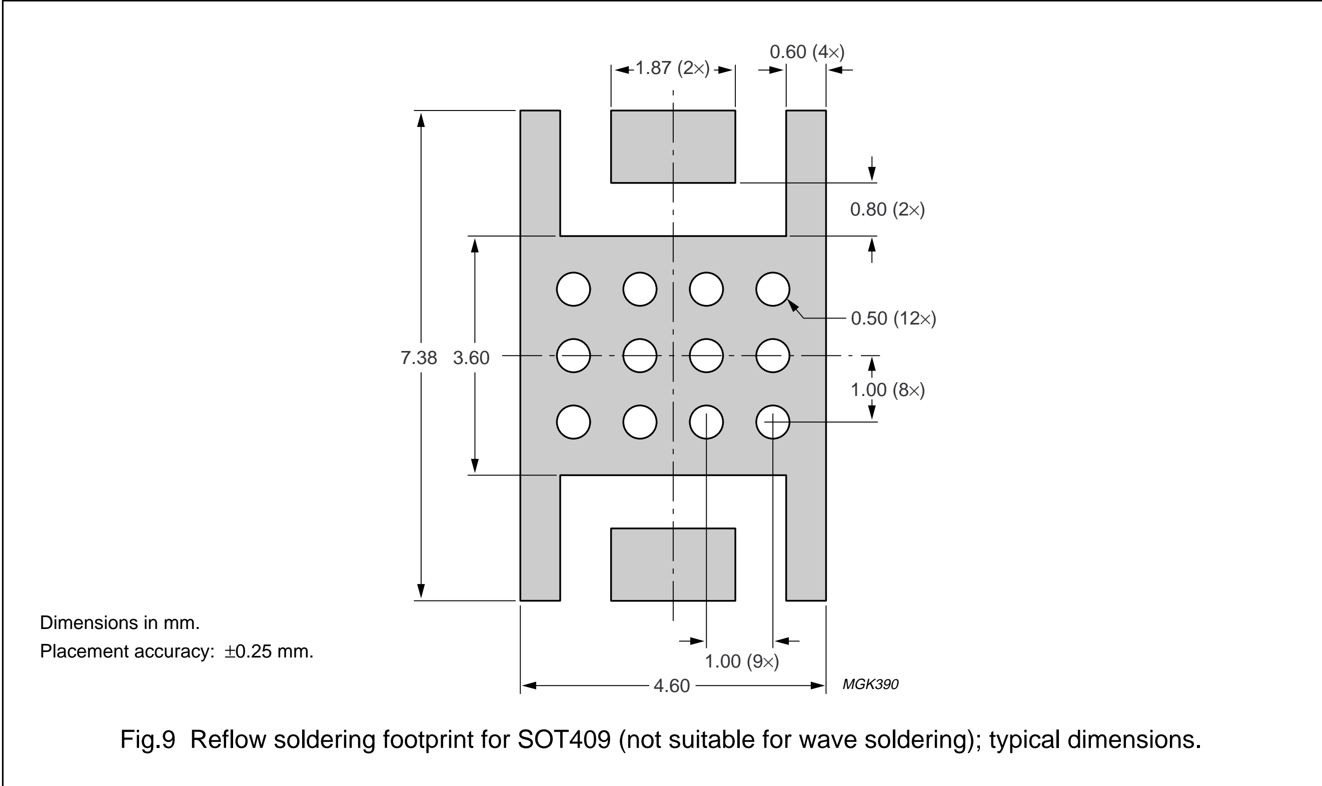


Fig.9 Reflow soldering footprint for SOT409 (not suitable for wave soldering); typical dimensions.

SOLDERING SMD MODULES

The indicated temperatures are those at the solder interfaces.

Advised solder types are types with a liquidus less than or equal to 210 °C.

Solder dots or solder prints must be large enough to wet the contact areas.

Soldering can be carried out using a conveyor oven, a hot air oven, an infrared oven or a combination of these ovens. Two reflow steps are permitted.

Hand soldering must be avoided because the soldering iron tip can exceed the maximum permitted temperature of 250 °C and damage the module.

The maximum allowed temperature is (see Fig.10):

t = 5 s at 250 °C.

The maximum ramp-up is 10 °C per second.

The maximum cool-down is 5 °C per second.

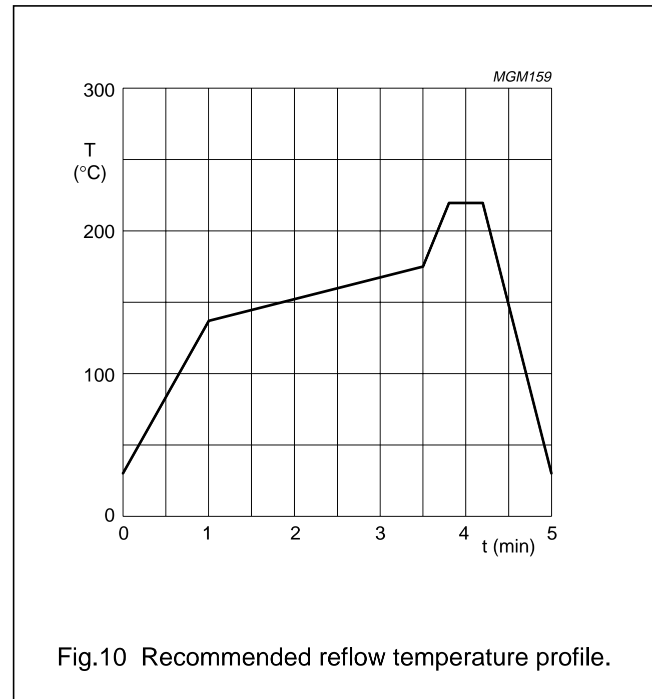


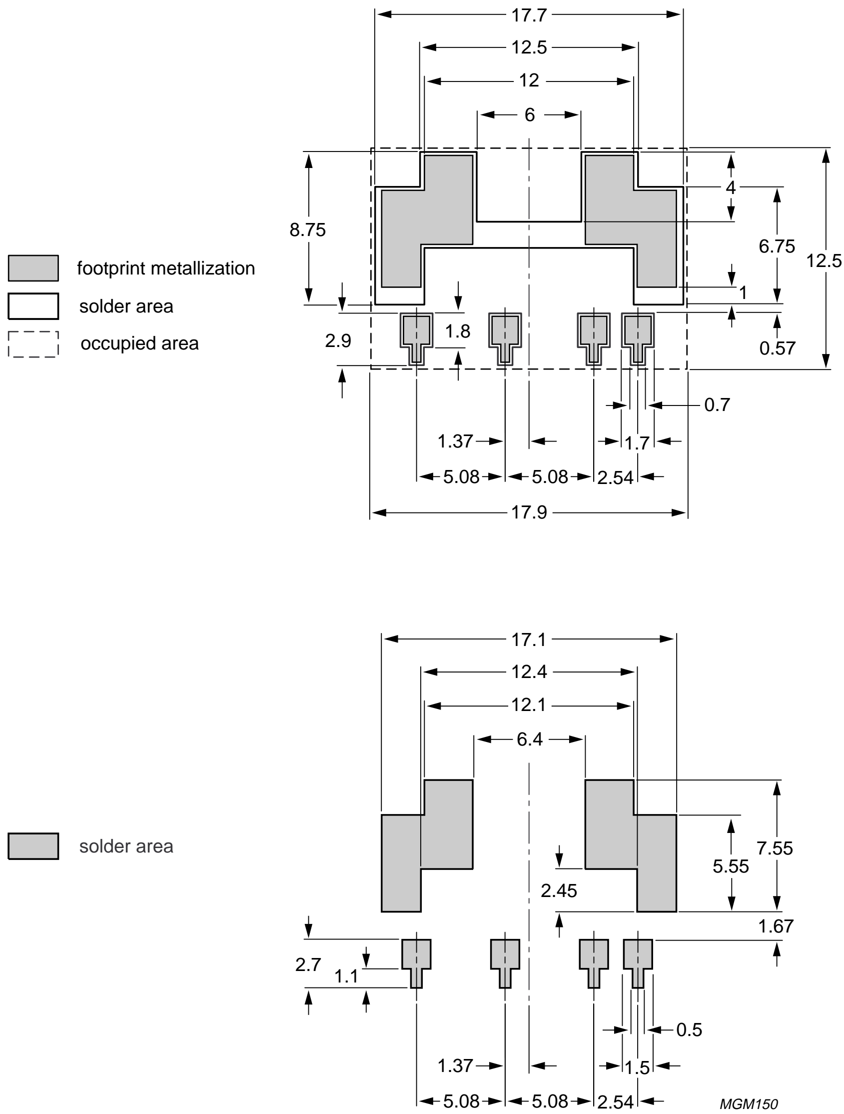
Fig.10 Recommended reflow temperature profile.

Cleaning

The following fluids may be used for cleaning:

- Alcohol
- Bio-Act (Terpene Hydrocarbon)
- Acetone.

Ultrasonic cleaning should not be used since this can cause serious damage to the product.



Dimensions in mm.

Fig.11 Footprint SOT388A/B/C.

MOUNTING FLANGED TRANSISTORS AND MODULES

Mounting recommendations for transistors

- Ensure holes in heatsinks are free from burrs.
- Minimum depth of tapped holes in heatsinks is 6 mm.
- Use 4-40 UNC-2A cheese-head screws with a flat washer to spread the joint pressure.
- For transistors dissipating up to 80 W, the heatsink thickness should be at least 3 mm copper (> 99.9% ETP-Cu) or 5 mm aluminium (99% Al). The thickness of the heatsink should be increased proportionally for transistors dissipating more power.
- The minimum flatness of the mounting area is 0.02 mm.
- Mounting area roughness should be less than 0.5 μm.
- Avoid, as much as possible, use of flux or flux solutions because flux can penetrate even hermetically sealed ceramic-capped transistors. Tin and wash the printed-circuit boards **before** mounting the transistors, then solder the transistors into place without using flux.
- Transistor leads may be tinned by dipping them full-length into a solder bath at a temperature of about 230 °C. No flux should be used during tinning.
- Recommended heatsink compounds: WPS II (silicone-free) from Austerlitz-Electronics; Comp. Trans. from KF; 340 from Dow Corning; Trans-Heat from E. Friis-Mikkelsen.
- When a transistor is removed from a heatsink, the flange, almost certainly, will have been distorted by the joint pressure. Grinding or lapping of the flange to the required flatness and smoothness is necessary before the transistor is remounted.

MOUNTING SEQUENCE

- Apply a thin layer of evenly-distributed heatsink compound to the flange.
- Position the device with flat washers in place.
- Tighten the screws until finger-tight (0.05 Nm).
- Further tighten the screws until the specified torque is reached (do not lubricate). Refer to Table 1 for torques.
- To lock mounting screws, allow about 30 minutes for them to bed-down after the specified torque has been applied, re-tighten to the specified torque and apply locking paint.

Table 1 Specified torque for flange mounted transistors

PACKAGE	TORQUE (Nm)	
	min	max
SOT119	0.6	0.75
SOT121	0.6	0.75
SOT123	0.6	0.75
SOT161	0.6	0.75
SOT171	0.6	0.75
SOT262	0.6	0.75
SOT268	0.6	0.75
SOT273	0.6	0.75
SOT279	0.6	0.75
SOT289	0.6	0.75
SOT324B	0.6	0.75
SOT390	–	0.5
SOT391	0.6	0.75
SOT391B	0.6	0.75
SOT422	–	0.5
SOT423	–	0.4
SOT437	–	0.5
SOT439	–	0.4
SOT440	–	0.4
SOT443	–	0.5
SOT445	–	0.4
SOT448	–	0.5
SOT460	–	0.5
SOT468	–	0.4
SOT469	–	0.4

Mounting recommendations for flanged modules

Modules (such as the SOT365) are manufactured using a ceramic substrate soldered to a copper or iron flange or mounting base; this causes a small thermal mismatch between these two components. A further thermal mismatch will exist between the mounting base and the heatsink to which it is mounted. Because of these mismatches, precautions must be taken to avoid unnecessary mechanical stresses being applied to the ceramic substrate and other components within the module resulting from variations in temperature during operating cycles.

Design of heatsink

To ensure that the maximum specified mounting base temperature will not be exceeded under maximum fault conditions, the module should always be mounted on a heatsink of suitable thermal resistance.

The mounting area of the heatsink should be flat and free from burrs and loose particles. Particular attention should be paid to the mounting hole areas. The maximum amount of bowing along the plane of the module should not exceed 0.1 mm. Where anodizing is used, the area under the module should be milled clean as the presence of anodizing under the module can result in high resistance earth paths, leading to oscillation and early failure, in addition to poor thermal contact.

The heatsink should be rigid and not prone to bowing under thermal cycling conditions. The thickness of a solid heatsink should not be less than 5 mm, to ensure a rigid assembly. On finned heatsinks, the module should be mounted along a plane parallel to the fins.

Mounting of modules

To ensure a good thermal contact and to prevent mechanical stresses when bolted down, the flatness of the mounting base is designed to be typically better than 100 µm.

The module should be mounted to the heatsink using 3 mm bolts with flat washers. The bolts should first be tightened to “finger tight” and then further tightened in alternating steps to a maximum torque of 0.4 to 0.6 Nm.

A thin, even layer of thermal compound should be used between the mounting base and the heatsink to achieve the best possible contact thermal resistance. Excessive use of thermal compound will result in an increase in thermal resistance and possible bowing of the mounting base; too little will also result in poor thermal resistance.

When mounted on the heatsink, the module leads can be soldered to the printed-circuit board. A soldering iron may be used up to a temperature of 250 °C for a maximum of 10 seconds at a distance of 2 mm from the plastic cap. ESD precautions must be taken to protect the device from electro-static damage.

Electrical connections

The main earth return path of all modules is via the mounting base; it is therefore important that the heatsink is well earthed and that return paths are kept as short as possible. Failure to ensure this may result in loss of output power or oscillation, which in turn will have a detrimental effect on the module life.

The RF output connection should be to correctly-designed 50 Ω terminations. Failure to do this will result in a mismatch being presented to the module, with a resulting reduction in module life.

THERMAL BEHAVIOUR OF TRANSISTORS

The thermal behaviour of packages is dependent on the materials used to construct the package. Table 2 gives an overview of the materials used in packages, while Table 3 shows the coefficients of linear thermal expansion for each material. The thermal expansion of the different parts can be calculated from this data.

Table 2 Overview of materials used in packages

PACKAGE	FLANGE			LEADFRAME				BACK-PAD	CERAMIC INSULATOR	
	Cu	W-Cu	Cu-Mo-Cu	ALLOY 42 (Fe58/Ni42)	Ni	KOVAR (Fe54/Ni29)	Cu	Cu	BeO	AIN
SOT119	√	–	–	√	–	–	–	–	√	–
SOT121	√	–	–	√	–	–	–	–	√	–
SOT123	√	–	–	√	–	–	–	–	√	–
SOT161	√	–	–	√	–	–	–	–	√	–
SOT171	√	–	–	√	–	–	–	–	√	–
SOT262	–	√	–	√	–	–	–	–	√	–
SOT268	–	√	–	√	–	–	–	–	√	–
SOT273	√	–	–	√	–	–	–	–	√	–
SOT279	√	–	–	√	–	–	–	–	√	–
SOT289	–	√	–	–	–	√	–	–	√	–
SOT324	–	√	–	√	–	–	–	–	√	–
SOT333	√	–	–	√	–	–	–	–	√	–
SOT390	–	√	–	√	–	–	–	–	√	–
SOT391	–	√	–	√	–	–	–	–	√	–
SOT391B	–	–	–	√	–	–	–	√	√	–
SOT409B	–	–	–	–	–	–	√	√	–	√
SOT422	√	–	–	–	√	–	–	–	√	–
SOT423	√	–	–	–	√	–	–	–	√	–
SOT437	–	√	–	√	–	–	–	–	√	–
SOT439	√	–	–	–	√	–	–	–	√	–
SOT440	√	–	–	–	–	√	–	–	√	–
SOT443	–	√	–	–	–	√	–	–	√	–
SOT445	√	–	–	–	–	√	–	–	√	–
SOT448	–	√	–	–	√	–	–	–	√	–
SOT460	–	√	–	√	–	–	–	–	√	–
SOT468	–	–	√	√	–	–	–	–	–	√
SOT511	–	–	–	–	–	–	–	–	–	√

Table 3 Coefficients of linear thermal expansion of package materials between 25 and 150 °C

SYMBOL	Cu	W-Cu	Cu-Mo-Cu	ALLOY 42 (Fe58/Ni42)	Ni	KOVAR (Fe54/Ni29)	BeO	AIN	UNIT
α	17.9	6.6	9.5 to 6.0	4.5	11.6	4.4	6.7	4.0	ppm/K

CAPSTAN HEADERS

Table 4 Mounting data for capstan headers

ITEM	MOUNTING STUD DIAMETER			TOLERANCE	UNIT
	1/4″	3/8″	1/2″		
Thread	8-32 UNC-2A(B)	10-32 UNF-2A(B)	1/4″ × 28 UNF-2A(B)	–	–
Maximum diameter of threaded stud	4.14	4.80	6.33	–	mm
Diameter of heatsink mounting hole	4.15	4.85	6.35	+0.05/–0	mm
Mounting nut thickness	3.5 and 5	5	5.5	–	mm
Mounting nut torque:					
minimum	0.75	1.5	2.3	–	Nm
maximum	0.85	1.7	2.7	–	Nm
Distance from heatsink to printed-circuit board	2.9	3.8	4.8	+0/–0.2	mm

Mounting recommendations

- Avoid, as much as possible, use of flux or flux solutions because flux can penetrate even hermetically sealed ceramic-capped transistors. Tin and wash the printed-circuit boards **before** mounting the power transistors, then solder the transistors into place without using flux.
- Transistor leads may be tinned by dipping them full-length into a solder bath at a temperature of about 230 °C. No flux should be used during tinning.
- Heatsink surfaces at the mounting hole are to be flat, parallel and free of burrs or oxidation.
- Do not use locking washers, their locking action can deteriorate in time due to the comparative softness of most heatsink materials. A flat washer can be used to spread the joint pressure.
- Ensure a positive clearance exists between leads and printed circuit board, this prevents upward lead-bending and consequent damage to the encapsulation
- Recommended heatsink compounds: WPS II (silicone-free) from Austerlitz-Electronics; Comp. Trans. from KF; 340 from Dow Corning; Trans-Heat from E. Friis-Mikkelsen.
- The full mounting nut torque should be applied only once in the life of a transistor. For pre-assembly testing, apply no more than two-thirds of the specified torque.

Mounting sequence

- Apply a thin layer of evenly-distributed heatsink compound to the heatsink.
- Position the device with a flat washer in place.
- Tighten the screws until finger-tight (0.05 Nm).
- Further tighten the screws until the specified torque is reached (do not lubricate); for torques, refer to the package outline section of this data handbook.
- To lock mounting screws, allow about 30 minutes for them to bed-down after the specified torque has been applied, re-tighten to the specified torque and apply locking paint.

HANDLING MOS DEVICES

Electrostatic charges

Electrostatic charges can exist in many things; for example, man-made-fibre clothing, moving machinery, objects with air blowing across them, plastic storage bins, sheets of paper stored in plastic envelopes, paper from electrostatic copying machines, and people. The charges are caused by friction between two surfaces, at least one of which is non-conductive. The magnitude and polarity of the charges depend on the different affinities for electrons of the two materials rubbing together, the friction force and the humidity of the surrounding air.

Electrostatic discharge is the transfer of an electrostatic charge between bodies at different potentials and occurs with direct contact or when induced by an electrostatic field. Our RF Power MOS transistors are sensitive to electrostatic discharge and, to avoid damage, the following precautions must be taken.

Work station

Figure 12 shows a working area suitable for safely handling electrostatic sensitive devices. It has a work bench, the surface of which is conductive or covered by an antistatic sheet. Typical resistivity for the bench surface is between 1 and 500 kΩ per cm^2. The floor should also be covered with antistatic material.

The following precautions should be observed:

- Persons at a work bench should be earthed via a wrist strap and a resistor.
- All mains-powered electrical equipment should be connected via an earth leakage switch.
- Equipment cases should be earthed.
- Relative humidity should be maintained between 50 and 65%.
- An ionizer should be used to neutralize objects with immobile static charges.

Receipt and storage

Our devices are packed for dispatch in antistatic conductive containers, usually boxes, tubes or blister tape. The fact that the contents are sensitive to electrostatic discharge is shown by warning labels on both primary and secondary packing.

The devices should be kept in their original packing whilst in storage. If a bulk container is partially unpacked, the unpacking should be performed at a protected work station. Any devices that are stored temporarily should be packed in conductive or antistatic packing or carriers.

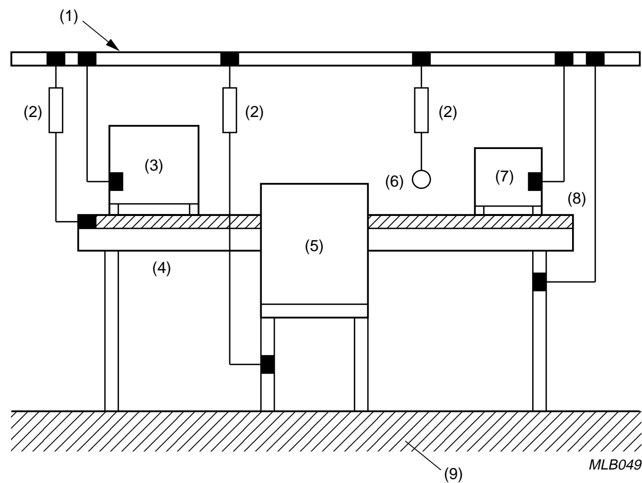
Assembly

The devices must be removed from their protective packing with earthed component pincers or short-circuit clips. Short-circuit clips must remain in place during mounting, soldering and cleansing/drying processes. Do not remove more devices from the storage packing than are needed at any one time. Production/assembly documents should state that the product contains electrostatic sensitive devices and that special precautions need to be taken.

All tools used during assembly, including soldering tools and solder baths, must be earthed. All hand tools should be of conductive or antistatic material and, where possible, should not be insulated.

Measuring and testing of completed circuit boards must be done at a protected work station. Place the soldered side of the circuit board on conductive or antistatic foam and remove the short-circuit clips. Remove the circuit board from the foam, holding the board only at the edges. Make sure the circuit board does not touch the conductive surface of the work bench. After testing, replace the circuit board on the conductive foam to await packing.

Assembled circuit boards should be handled in the same way as unmounted devices. They should also carry warning labels and be packed in conductive or antistatic packing.



(1) Earthing rail.
(2) Resistor (500 kΩ ±10%, 0.5 W).
(3) Ionizer.
(4) Work bench.
(5) Chair.
(6) Wrist strap.
(7) Electrical equipment.
(8) Conductive surface/antistatic sheet.
(9) Antistatic floor.

Fig.12 Protected work station.

TAPE AND REEL PACKING

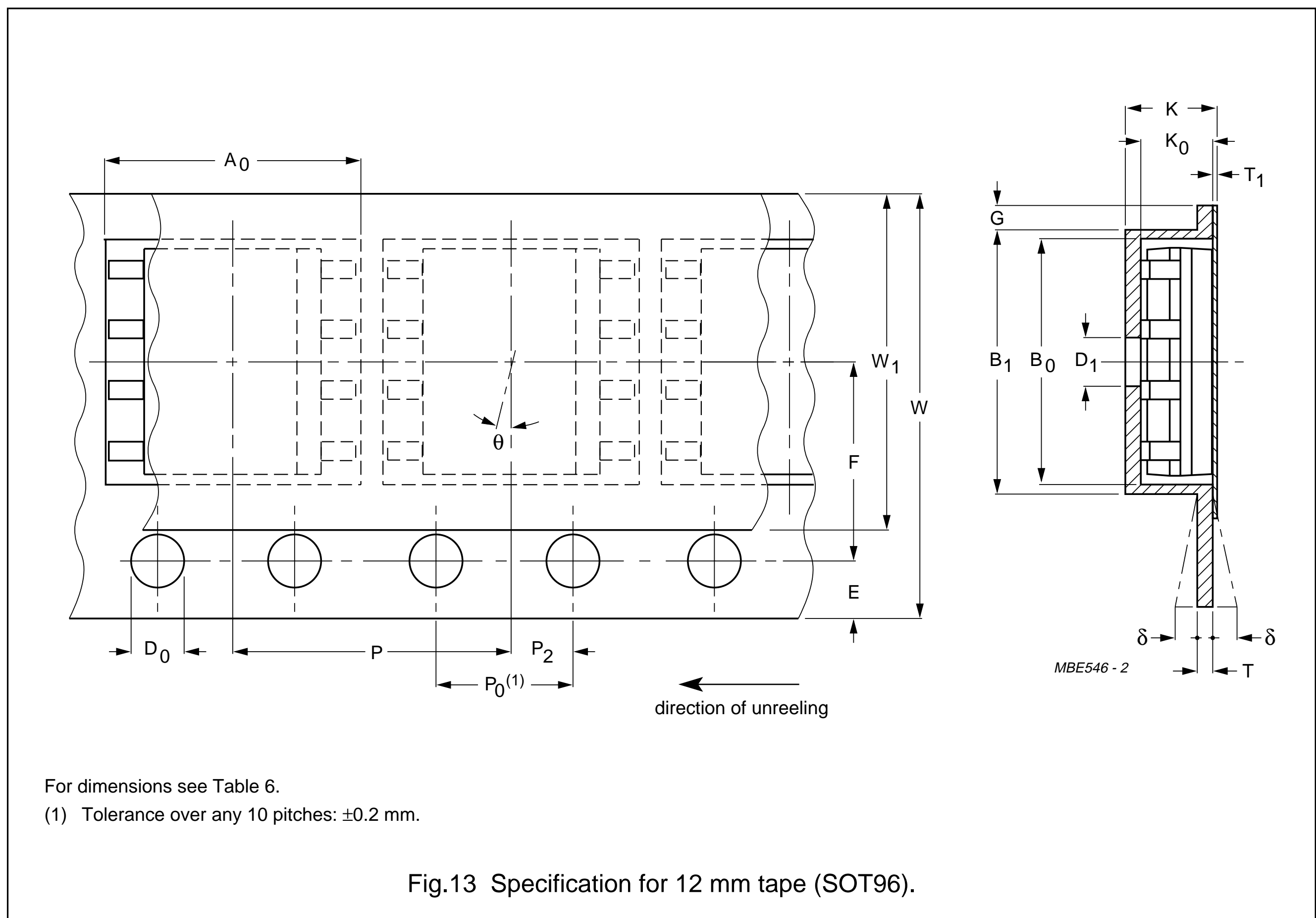
Packing types

Table 5 Packing quantities per reel

PACKAGE	TAPE WIDTH (mm)	REEL SIZE (mm)	QUANTITY PER REEL	12NC[1] ends with:
SOT96 (SO8)	12	330	2500	...118
SOT223	12	180	1000	...115
	12	330	4000	...135
SOT338A/B	32	330	750	...135
SOT338C	32	330	800	...135
SOT421A	44	330	600	...135

Note

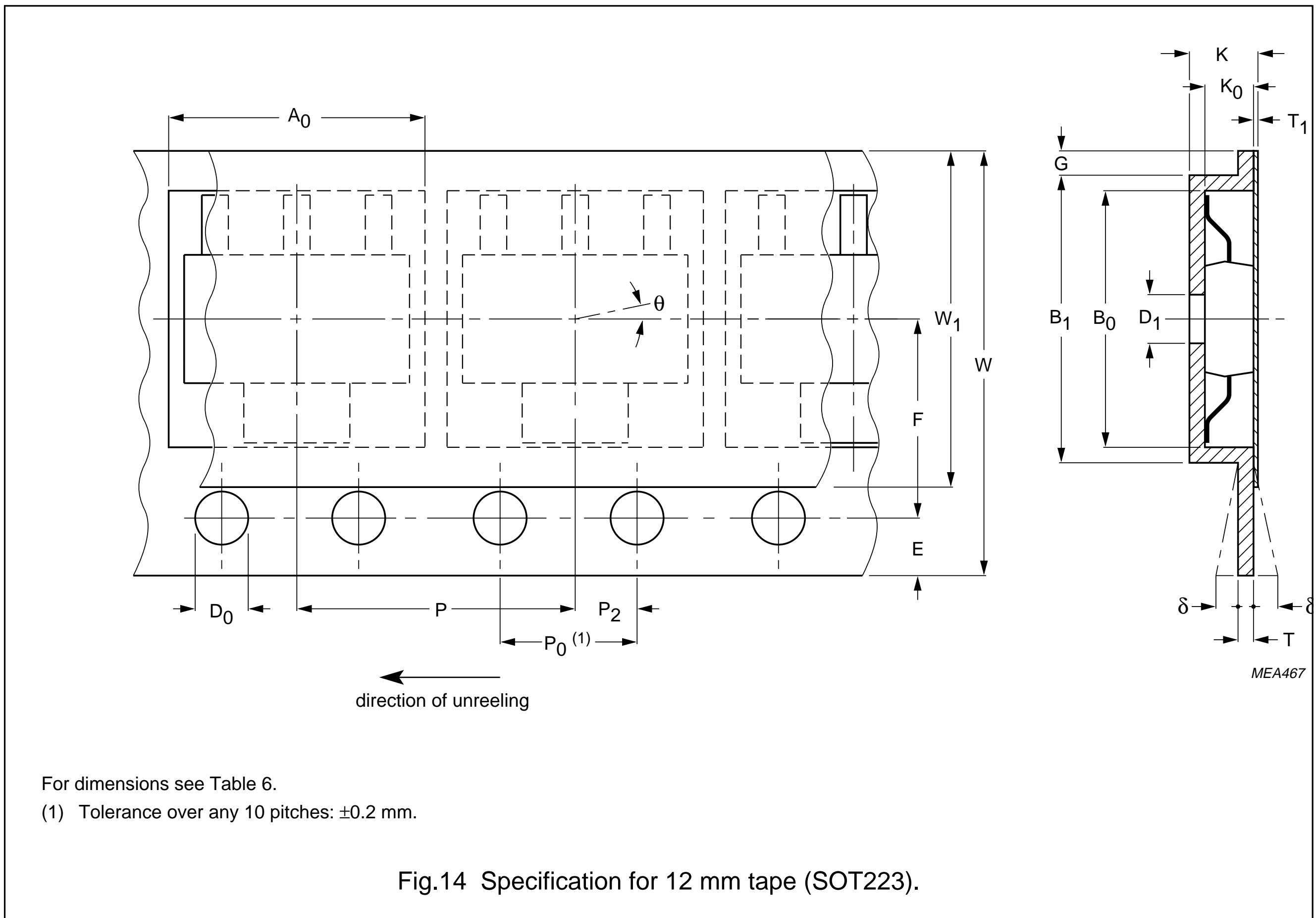
1. 12NC is the Philips twelve-digit ordering code.



For dimensions see Table 6.

(1) Tolerance over any 10 pitches: ±0.2 mm.

Fig.13 Specification for 12 mm tape (SOT96).



For dimensions see Table 6.

(1) Tolerance over any 10 pitches: ±0.2 mm.

Fig.14 Specification for 12 mm tape (SOT223).

Table 6 Tape dimensions (in mm)

DIMENSION (Figs 13 and 15)	**12 mm CARRIER TAPE**	**TOLERANCE**
Overall dimensions		
W	12.0	±0.2
K	<2.4	–
G	>0.75	–
Sprocket holes; note 1		
D_0	1.5	+0.1/–0
E	1.75	±0.1
P_0	4.0	±0.1
Relative placement compartment		
P_2	2.0	±0.1
F	5.5	±0.05
Compartment		
A_0	Compartment dimensions depend on package size. Maximum clearance between device and compartment is 0.3 mm; the minimum clearance ensures that the device is not totally restrained within the compartment.	
B_0		
B_1		
K_0		
D_1	>1.5	–
P	8.0	±0.1
θ	<15°	–
Cover tape; note 2		
W_1	<9.5	–
T_1	<0.1	–
Carrier tape		
W	12.0	±0.2
T	<0.2	–
δ	<0.3	–

Notes

1. Tolerance over any 10 pitches ±0.2 mm.
2. The cover tape shall not overlap the tape or sprocket holes.

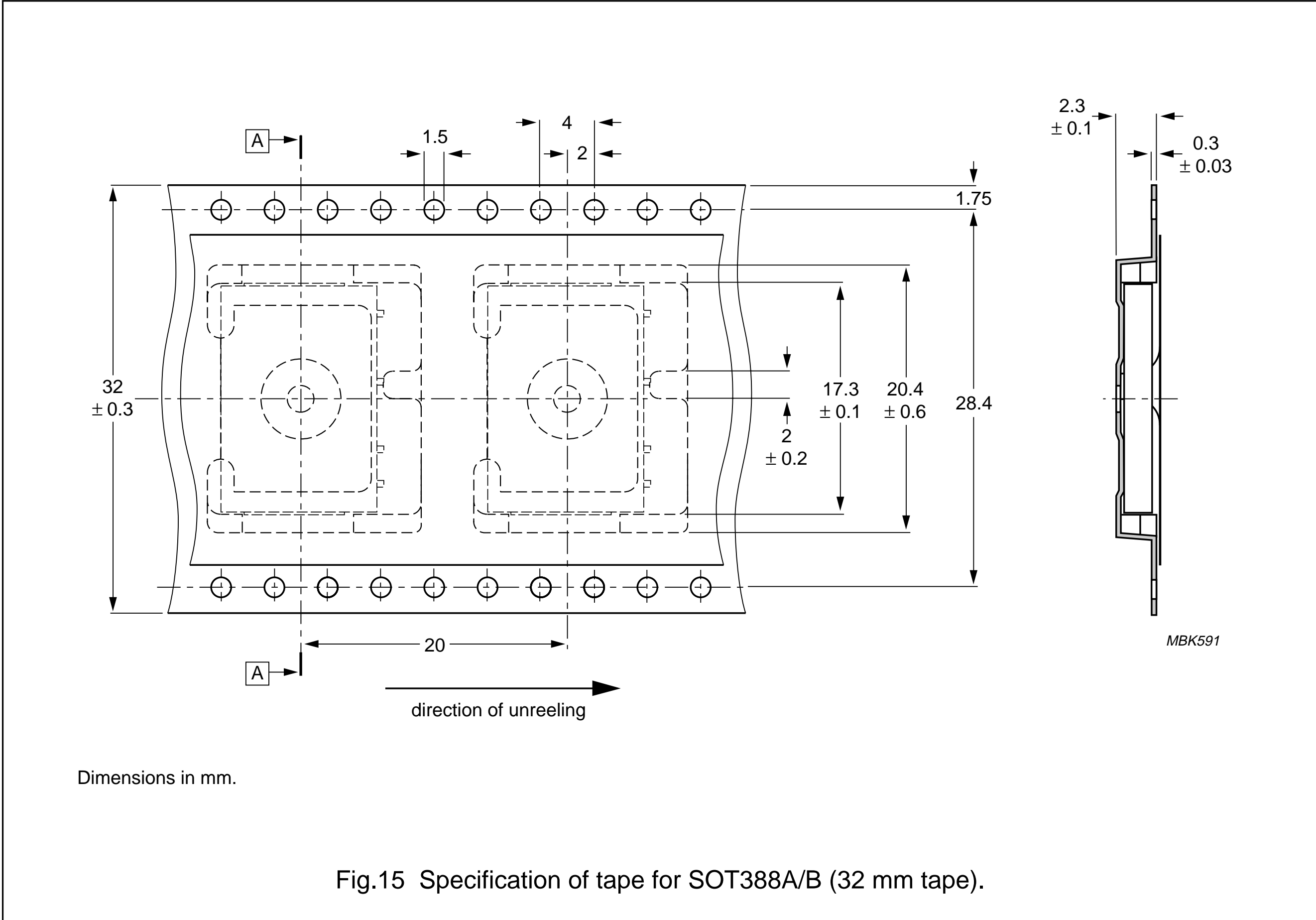


Fig.15 Specification of tape for SOT388A/B (32 mm tape).

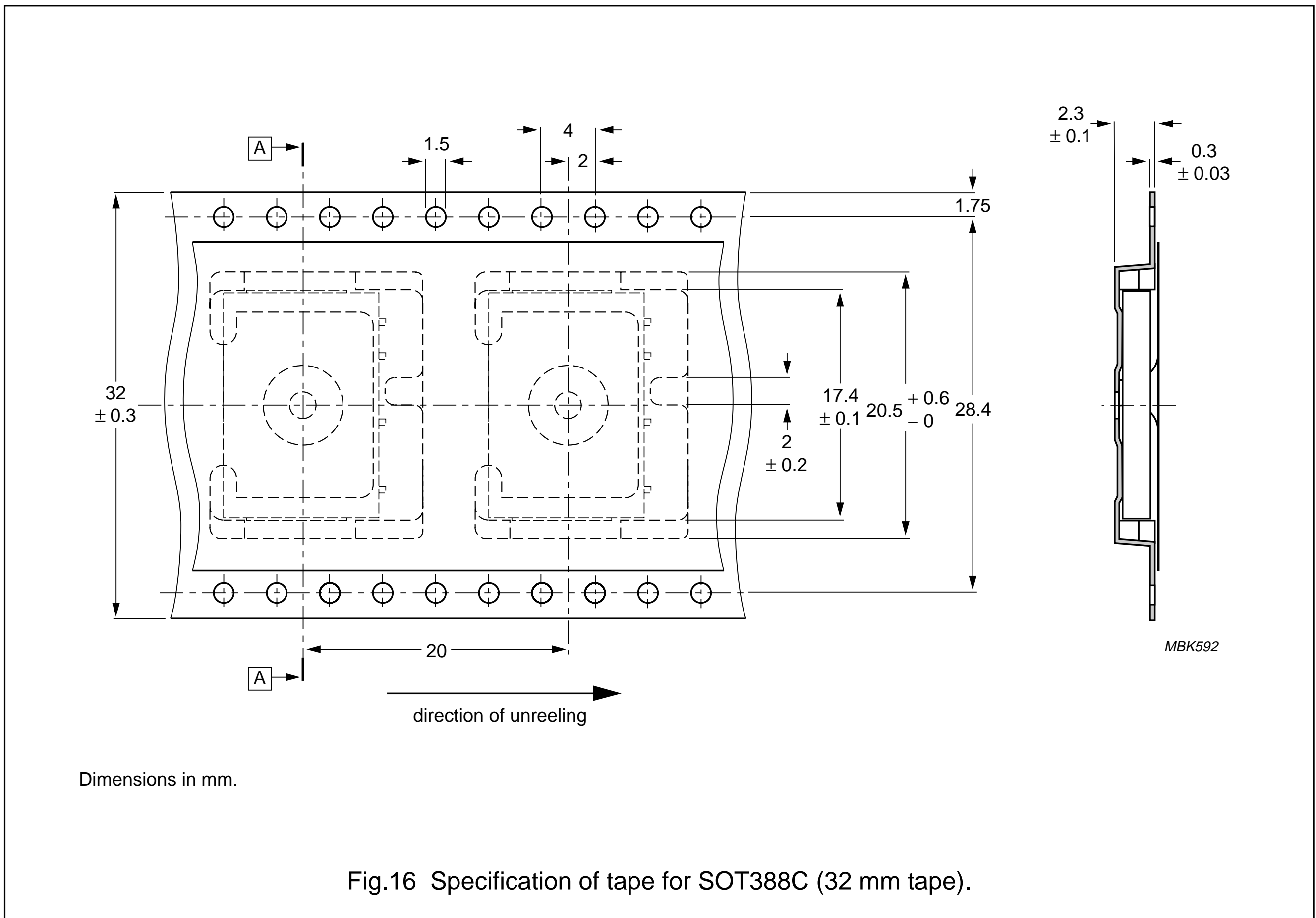
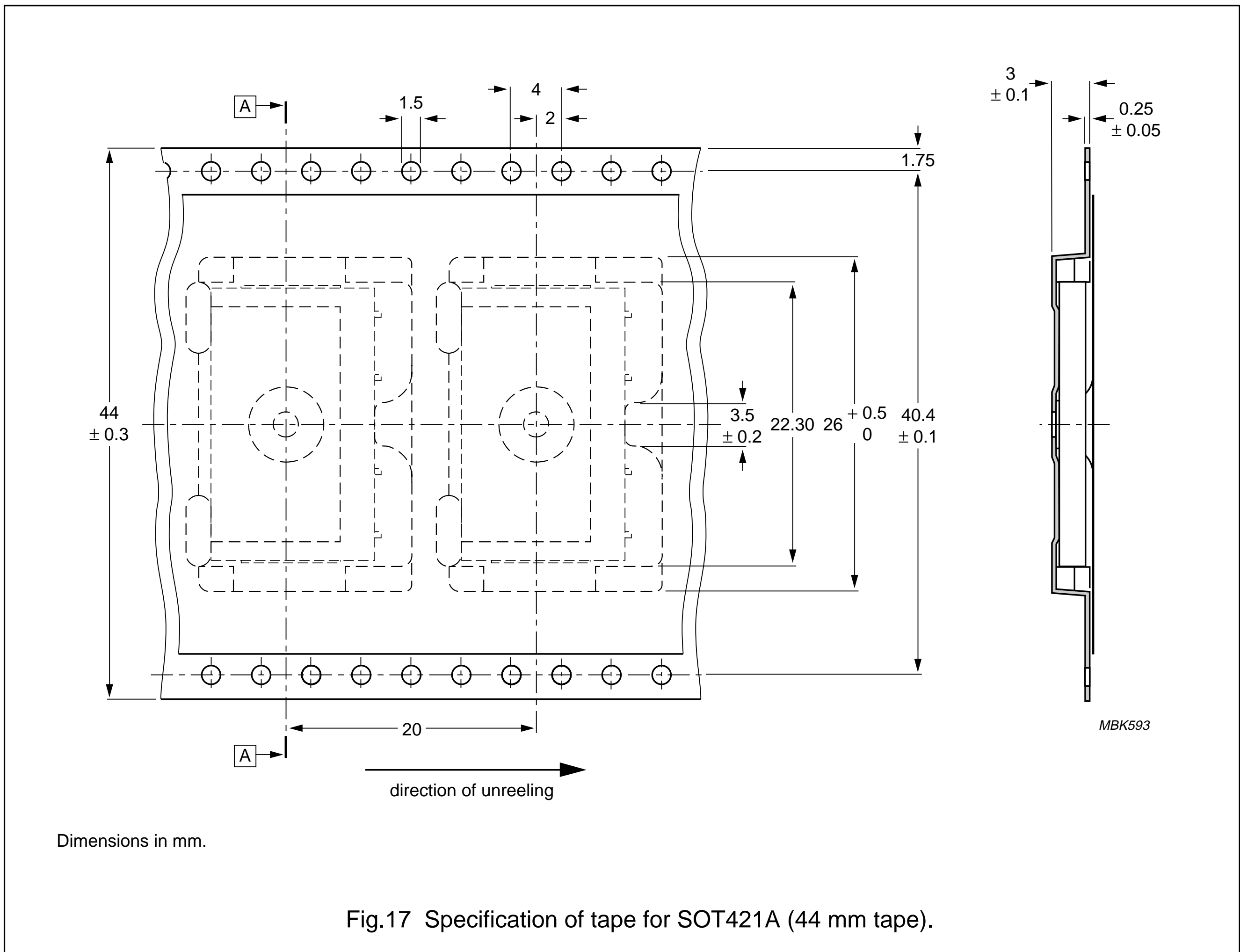


Fig.16 Specification of tape for SOT388C (32 mm tape).



Dimensions in mm.

Fig.17 Specification of tape for SOT421A (44 mm tape).

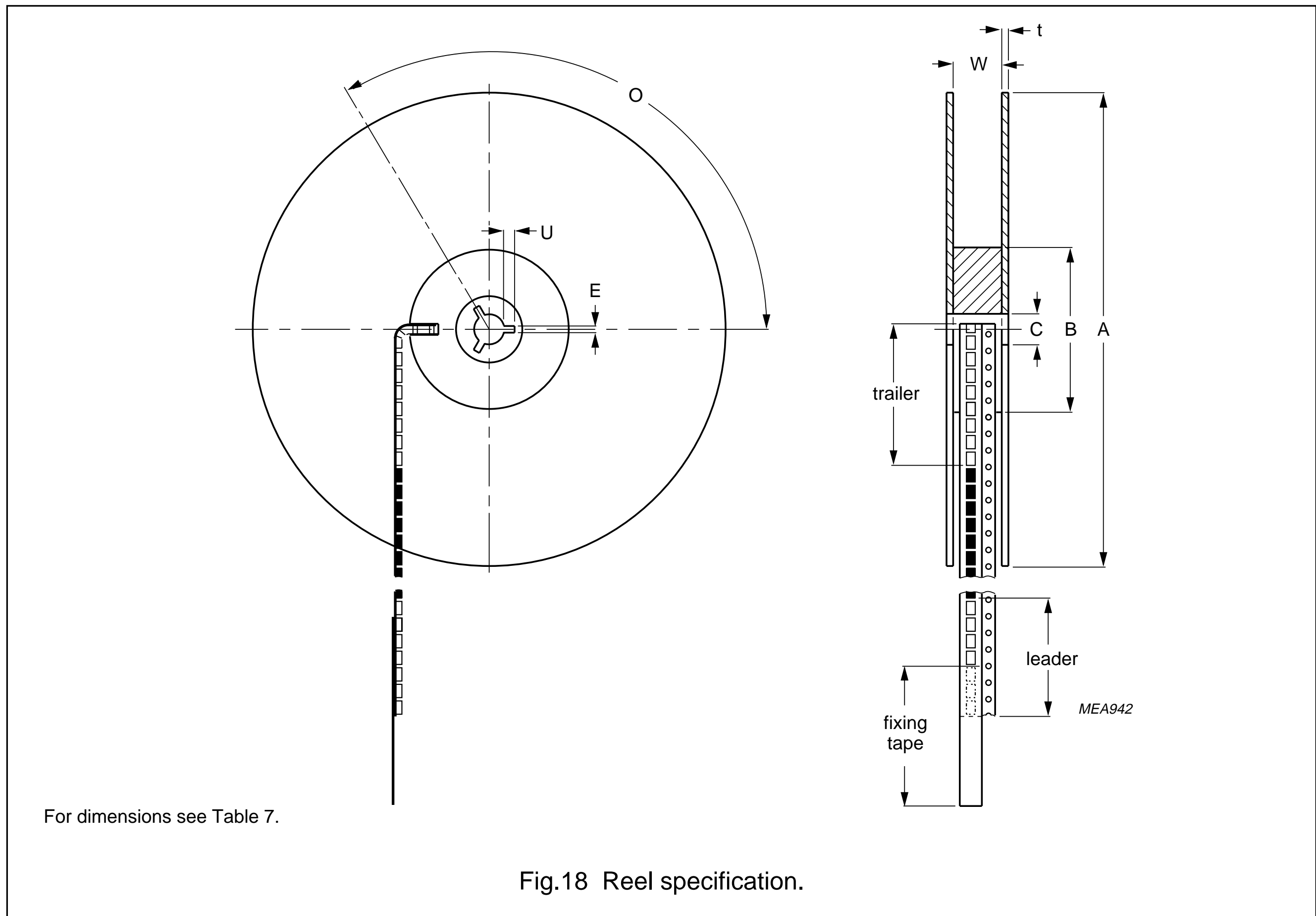


Fig.18 Reel specification.

Table 7 Reel dimensions (in mm)

DIMENSION (see Fig.18)	12 mm CARRIER TAPE	TOLERANCE	40 mm CARRIER TAPE	TOLERANCE
Flange				
A	180[1] or 330	±0.5	330	–
t	1.5	+0.5/–0.1	3	–
W	12.4	18.0+0.2	44.4	+2/–0
Hub				
B	62	±1.5	101	±1.5
C	12.75	+0.15/–0.2	13	±1.5
Key slot				
E	2	±0.2	1.5	–
U	4	±0.5	3.6	–
O	120°	–	120°	–

Note

1. Large reel diameter depends on individual package (286 or 350).

THERMAL CONSIDERATIONS

Introduction

This chapter only gives a brief overview of the thermal characteristics of discrete semiconductors. For a more in-depth explanation, refer to Data Handbook SC18 “Discrete Semiconductor Packages”, ordering number 9397 750 02418.

Thermal resistance

Circuit performance and long-term reliability are affected by the temperature of the transistor die. Normally, both are improved by keeping the die temperature (junction temperature) low.

Electrical power dissipated in any semiconductor device is a source of heat. This increases the temperature of the die about some reference point, normally an ambient temperature of 25 °C in still air. The size of the increase in temperature depends on the amount of power dissipated in the circuit and the net thermal resistance between the heat source and the reference point.

Devices lose most of their heat by conduction when mounted on a a printed board, a substrate or heatsink. Referring to Fig.19 (for surface mounted devices mounted on a substrate), heat conducts from its source (the junction) via the package leads and soldered connections to the substrate. Some heat radiates from the package into the surrounding air where it is dispersed by convection or by forced cooling air. Heat that radiates from the substrate is dispersed in the same way.

The elements of thermal resistance shown in Fig.20 are defined as follows:

$R_{th\ j\text{-}mb}$	thermal resistance from junction to mounting base
$R_{th\ j\text{-}c}$	thermal resistance from junction to case
$R_{th\ j\text{-}s}$	thermal resistance from junction to soldering point
$R_{th\ c\text{-}a}$	thermal resistance from case to ambient
$R_{th\ j\text{-}a}$	thermal resistance from junction to ambient.

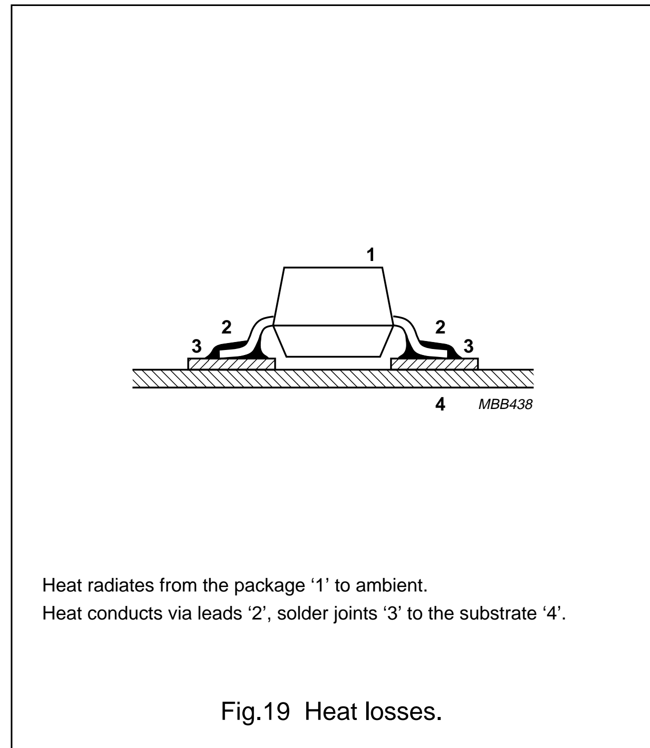


Fig.19 Heat losses.

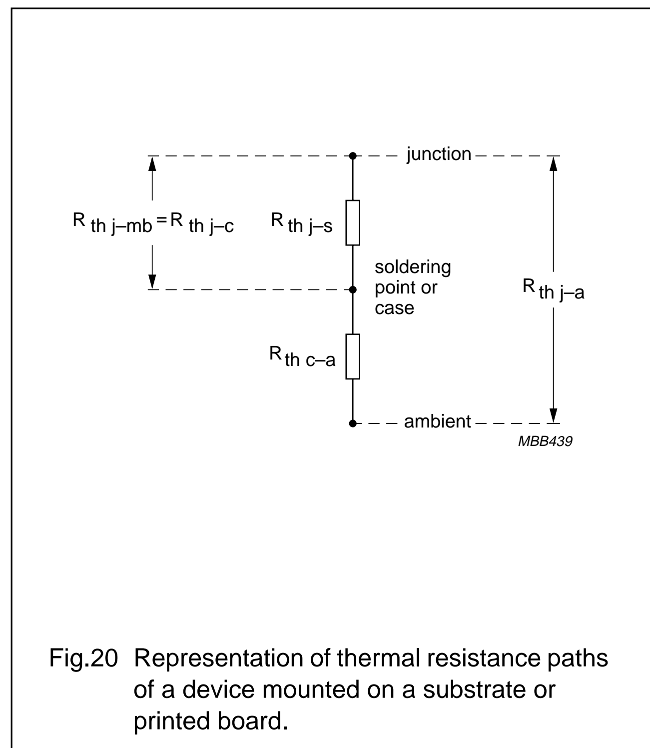


Fig.20 Representation of thermal resistance paths of a device mounted on a substrate or printed board.

The temperature at the junction depends on the ability of the package and its mounting to transfer heat from the junction region to the ambient environment. The basic relationship between junction temperature and power dissipation is:

$T_{j\ max} = T_{amb} + P_{tot\ max}(R_{th\ j\text{-}s} + R_{th\ s\text{-}a})$
$= T_{amb} + P_{tot\ max}(R_{th\ j\text{-}a})$

where:

$T_{j\ max}$ is the maximum junction temperature

T_{amb} is the ambient temperature

$P_{tot\ max}$ is the maximum power handling capability of the device, including the effects of external loads when applicable.

In the expression for $T_{j\ max}$, only T_{amb} and $R_{th\ s\text{-}a}$ can be varied by the user. The package mounting technique and the flow of cooling air are factors that affect $R_{th\ s\text{-}a}$. The device power dissipation can be controlled to a limited extent but under recommended usage, the supply voltage and circuit loading dictate a fixed power maximum. The $R_{th\ j\text{-}s}$ value is essentially independent of external mounting method and cooling air; but is sensitive to the materials used in the package construction, the die bonding method and the die area, all of which are fixed.

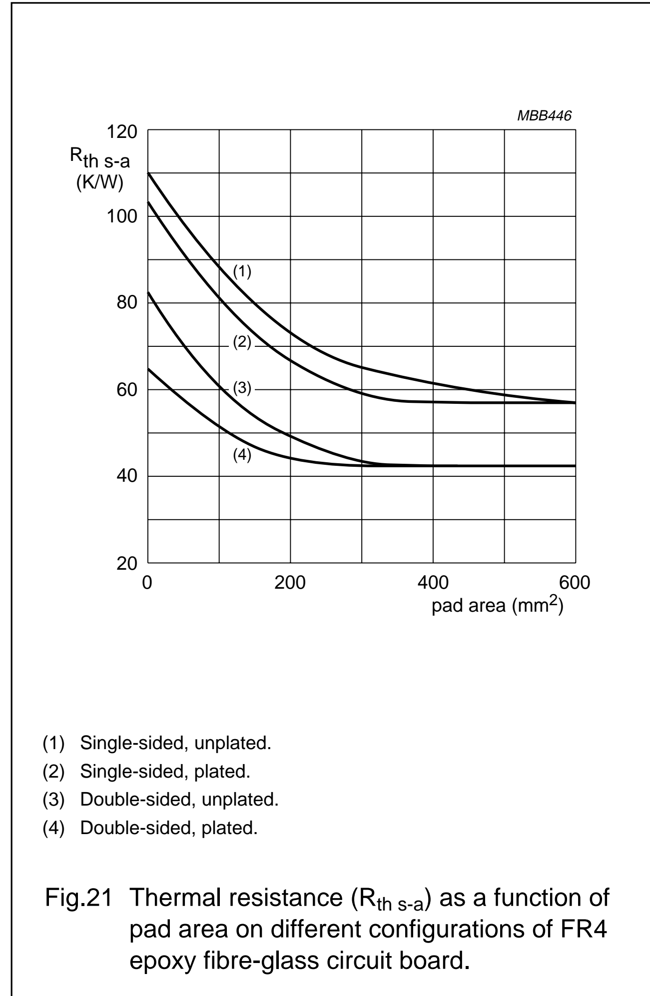
For applications where the temperature of the case is stabilized by a large or temperature-controlled heatsink, the junction temperature can be calculated from

$T_j = T_{case} + P_{tot} \times R_{th\ j\text{-}c}$ or, using the soldering point definition, from $T_j = T_{solder} + P_{tot} \times R_{th\ j\text{-}s}$.

Values of $T_{j\ max}$ and $R_{th\ j\text{-}s}$, or $R_{th\ j\text{-}c}$ or $R_{th\ j\text{-}a}$ are given in the device data sheets.

Thermal resistance ($R_{th\ s\text{-}a}$)

The thermal resistance from soldering point to ambient, and that from case to ambient depends on the shape and material of the tracks and substrate as illustrated in Figure 21.



(1) Single-sided, unplated.
(2) Single-sided, plated.
(3) Double-sided, unplated.
(4) Double-sided, plated.

Fig.21 Thermal resistance ($R_{th\ s\text{-}a}$) as a function of pad area on different configurations of FR4 epoxy fibre-glass circuit board.

SUNSTAR 商斯达实业集团是集研发、生产、工程、销售、代理经销 、技术咨询、信息服务等为一体的高科技企业，是专业高科技电子产品生产厂家，是具有 10 多年历史的专业电子元器件供应商，是中国最早和最大的仓储式连锁规模经营大型综合电子零部件代理分销商之一,是一家专业代理和分銷世界各大品牌 IC 芯片和電子元器件的连锁经营綜合性国际公司，专业经营进口、国产名厂名牌电子元件，型号、种类齐全。在香港、北京、深圳、上海、西安、成都等全国主要电子市场设有直属分公司和产品展示展销窗口门市部专卖店及代理分销商,已在全国范围内建成强大统一的供货和代理分销网络。 我们专业代理经销、开发生产电子元器件、集成电路、传感器、微波光电元器件、工控机/DOC/DOM 电子盘、专用电路、单片机开发、MCU/DSP/ARM/FPGA 软件硬件、二极管、三极管、模块等，是您可靠的一站式现货配套供应商、方案提供商、部件功能模块开发配套商。商斯达实业公司拥有庞大的资料库，有数位毕业于著名高校——有中国电子工业摇篮之称的西安电子科技大学（西军电）并长期从事国防尖端科技研究的高级工程师为您精挑细选、量身订做各种高科技电子元器件，并解决各种技术问题。

微波光电部专业代理经销高频、微波、光纤、光电元器件、组件、部件、模块、整机；电磁兼容元器件、材料、设备；微波 CAD、EDA 软件、开发测试仿真工具；微波、光纤仪器仪表。欢迎国外高科技微波、光纤厂商将优秀产品介绍到中国、共同开拓市场。长期大量现货专业批发高频、微波、卫星、光纤、电视、CATV 器件： 晶振、VCO、连接器、PIN 开关、变容二极管、开关二极管、低噪晶体管、功率电阻及电容、放大器、功率管、MMIC、混频器、耦合器、功分器、振荡器、合成器、衰减器、滤波器、隔离器、环行器、移相器、调制解调器；光电子元器件和组件：红外发射管、红外接收管、光电开关、光敏管、发光二极管和发光二极管组件、半导体激光二极管和激光器组件、光电探测器和光接收组件、光发射接收模块、光纤激光器和光放大器、光调制器、光开关、DWDM 用光发射和接收器件、用户接入系统光光收发器件与模块、光纤连接器、光纤跳线/尾纤、光衰减器、光纤适 配器、光隔离器、光耦合器、光环行器、光复用器/转换器；无线收发芯片和模组、蓝牙芯片和模组。

更多产品请看本公司产品专用销售网站:

商斯达中国传感器科技信息网：http://www.sensor-ic.com/

商斯达工控安防网：http://www.pc-ps.net/

商斯达电子元器件网：http://www.sunstare.com/

商斯达微波光电产品网:HTTP://www.rfoe.net/

商斯达消费电子产品网://www.icasic.com/

商斯达实业科技产品网://www.sunstars.cn/ 微波元器件销售热线：

地址：深圳市福田区福华路福庆街鸿图大厦 1602 室

电话：0755-82884100 83397033 83396822 83398585

传真：0755-83376182 （0）13823648918 MSN: SUNS8888@hotmail.com

邮编：518033 E-mail:szss20@163.com QQ: 195847376

深圳赛格展销部：深圳华强北路赛格电子市场 2583 号 电话：0755-83665529 25059422

技术支持: 0755-83394033 13501568376

欢迎索取免费详细资料、设计指南和光盘 ；产品凡多，未能尽录，欢迎来电查询。

北京分公司：北京海淀区知春路 132 号中发电子大厦 3097 号

TEL：010-81159046 82615020 13501189838 FAX：010-62543996

上海分公司：上海市北京东路 668 号上海赛格电子市场 D125 号

TEL：021-28311762 56703037 13701955389 FAX：021-56703037

西安分公司：西安高新开发区 20 所(中国电子科技集团导航技术研究所)

西安劳动南路 88 号电子商城二楼 D23 号

TEL：029-81022619 13072977981 FAX:029-88789382